

# Superconductor-insulator transition in MoC ultrathin films

## Transport and STM studies

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*(samples & microwave measurements)*

# SUPPRESSION OF $T_c$ IN THIN FILMS

first noticed in 1938, Nature (London) by Shalnikov in Pb and Sn films ~ hundreds of nm thin



## ~ LOCALISATION IN METALS & SUPERCONDUCTORS

Ioffe



Ioffe-Regel criterion, *Prog. Semicond.* 1960

When  $l_{min} \sim a$ , electrons localize  
( $l$  - electron's mean free path &  $a$  - lattice constant)

$$k_F l_{min} \approx 1 \quad (k_F \cong 1/a) \quad (n = k_F^2 / 2\pi)$$



Regel

Minimum metallic conductivity  
(maximum sheet resistance)

$$\sigma_{2D} = \frac{n e^2 \tau}{m} = \frac{k_F^2 / 2\pi e^2 l}{m v_F} = \frac{k_F^2 / 2\pi e^2 l}{\hbar k_F} = \frac{e^2}{h} = 1/25.82 \text{ k}\Omega$$

localization of Cooper pairs  $q=2e$

$$\sigma_{2D} = \frac{4e^2}{h} = 1/6.45 \text{ k}\Omega$$

# SUPERCONDUCTOR - INSULATOR TRANSITION (SIT)

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18 JUNE 1990

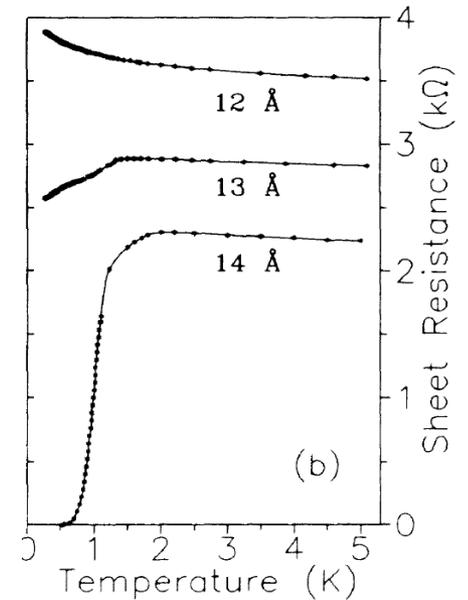
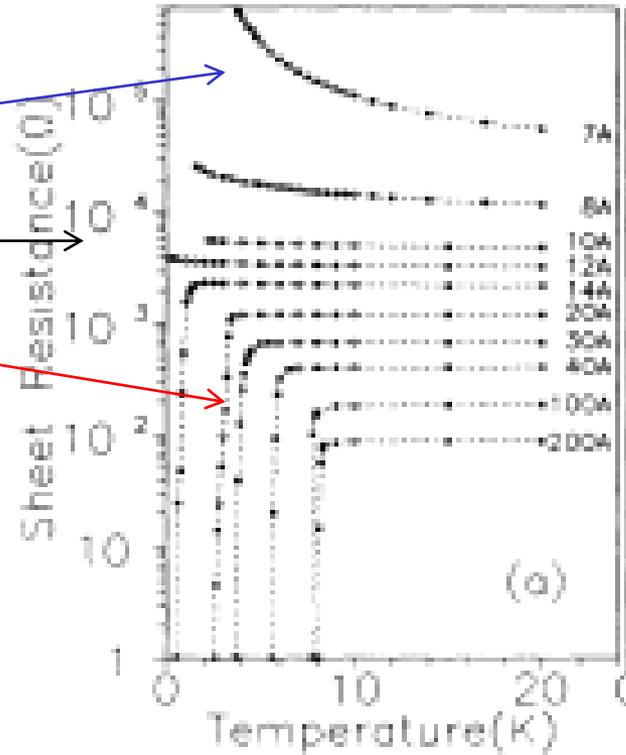
## Critical Sheet Resistance for the Suppression of Superconductivity in Thin Mo-C Films

S. J. Lee and J. B. Ketterson

insulating films

separatrix @  $R_Q \sim 3 \text{ k}\Omega$   
( $< 6.45 \text{ k}\Omega$ )

<superconducting films



What is the physics of

1. suppression of  $T_c$  on sc side
2. SIT transition
3. insulating state





# WHAT CONTROLS $T_c$ ?

PHYSICAL REVIEW B

VOLUME 1, NUMBER 3

1 FEBRUARY 1970

## Destruction of Superconductivity in Disordered Near-Monolayer Films\*

MYRON STRONGIN, R. S. THOMPSON, O. F. KAMMERER AND J. E. CROW

Brookhaven National Laboratory, Upton, New York 11903

$T_c$  versus resistivity  $\rho$

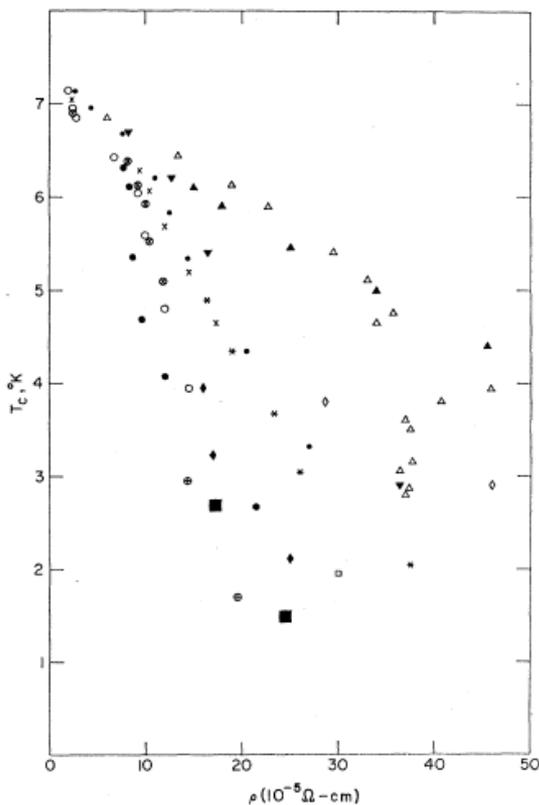


FIG. 7.  $T_c$  versus resistivity  $\rho$  (see Fig. 5 for symbol notation).

$T_c$  versus inversed thickness

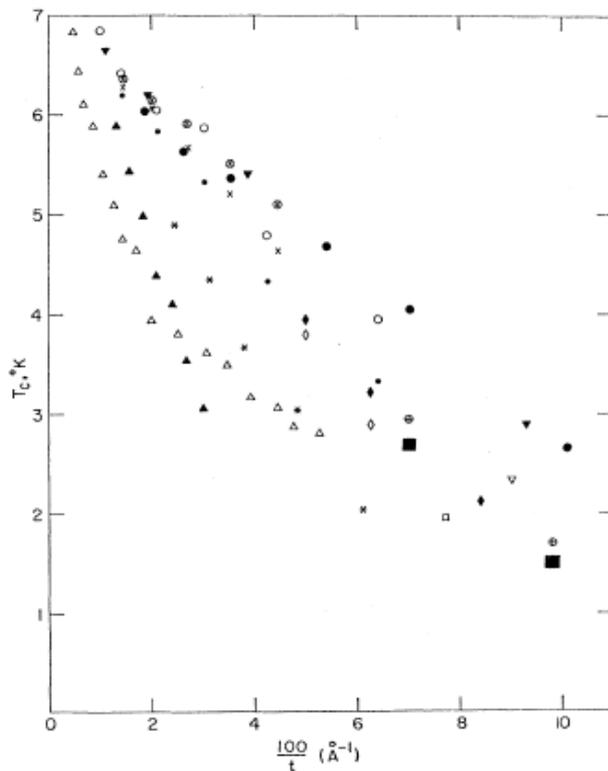


FIG. 6.  $T_c$  versus inverse thickness (see Fig. 5 for symbol notation).

$T_c$  versus sheet resistance

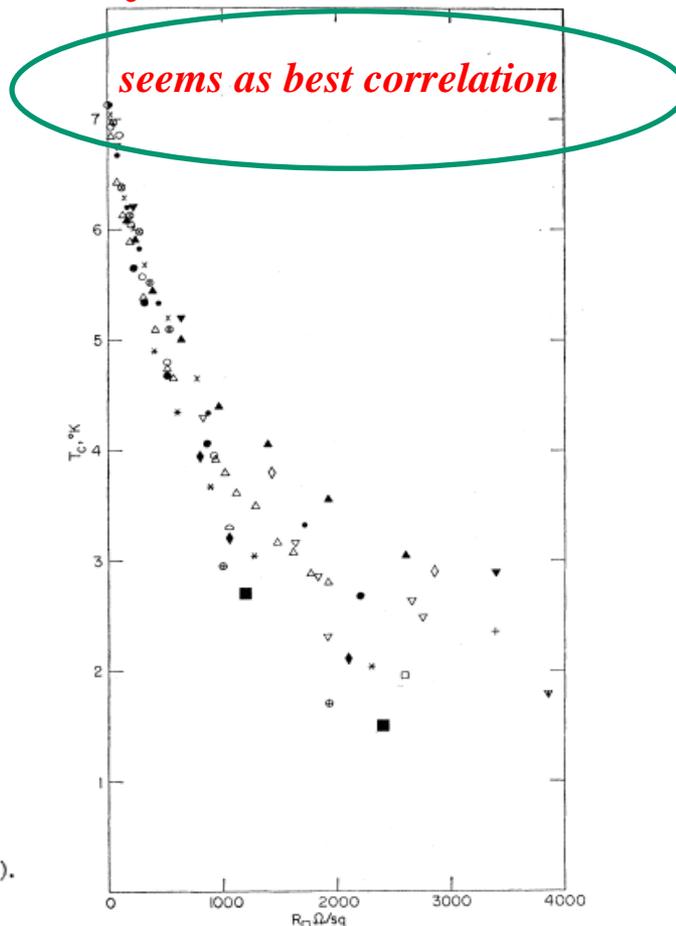


FIG. 5.  $T_c$  versus  $R_{sq}$  where  $R_{sq}$  is the resistance/sq area:  $\oplus$ ,  $\blacksquare$ —Pb on Ge;  $+$ —Pb on  $Al_2O_3$ ;  $\blacklozenge$ ,  $\circ$ —Pb on Ge (deposited at room temperature);  $*$ —Bi on  $SiO_2$ ;  $\nabla$ ,  $\otimes$ ,  $\circ$ ,  $\bullet$ ,  $\odot$ ,  $\Delta$ ,  $\blacktriangle$ ,  $\blacktriangledown$ —Pb on  $SiO_2$ .

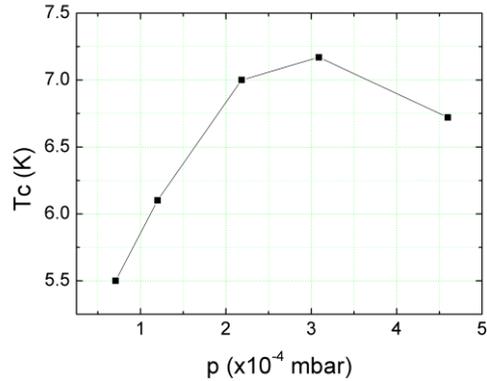
Pb and Bi films on dif. substrates



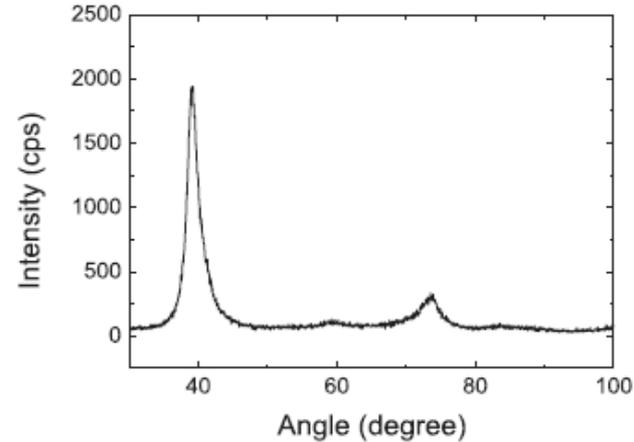
# Preparation of our MoC thin films

Reactive magnetron sputtering, target Mo 99.95%  
in mixture of Ar and acetylene gas on single crystalline sapphire @ 200 C

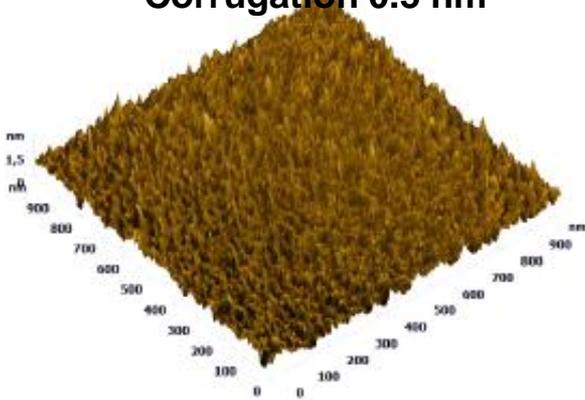
## optimization of acetylene pressure



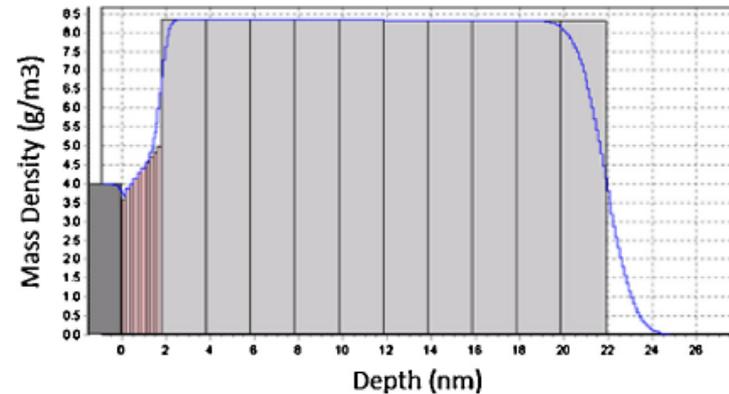
## RTG analysis shows MoC peak



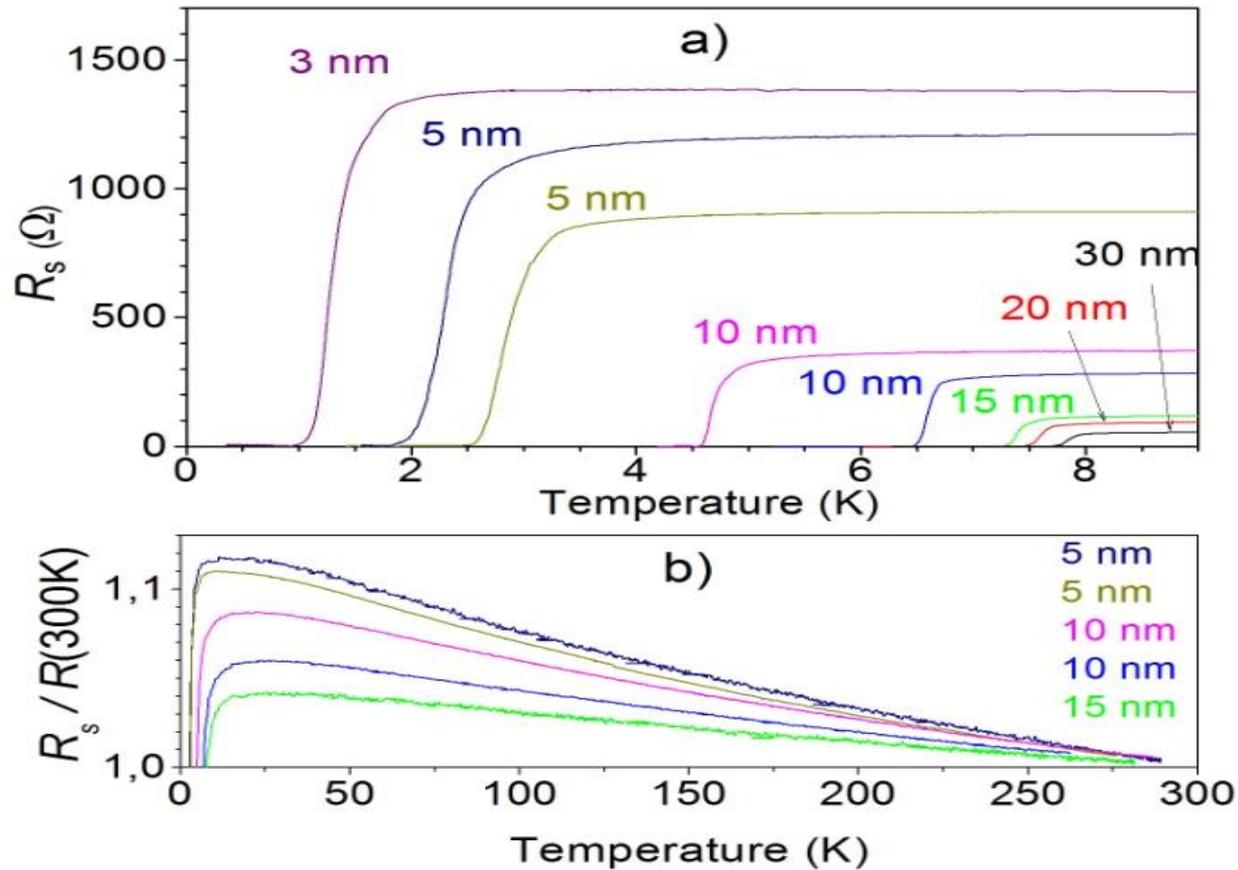
AFM on 1 x 1 mm<sup>2</sup>  
Corrugation 0.5 nm



Thickness controlled by sputtering time  
~10 nm/min checked by XRR  
Density profile



# Transport in MoC thin films

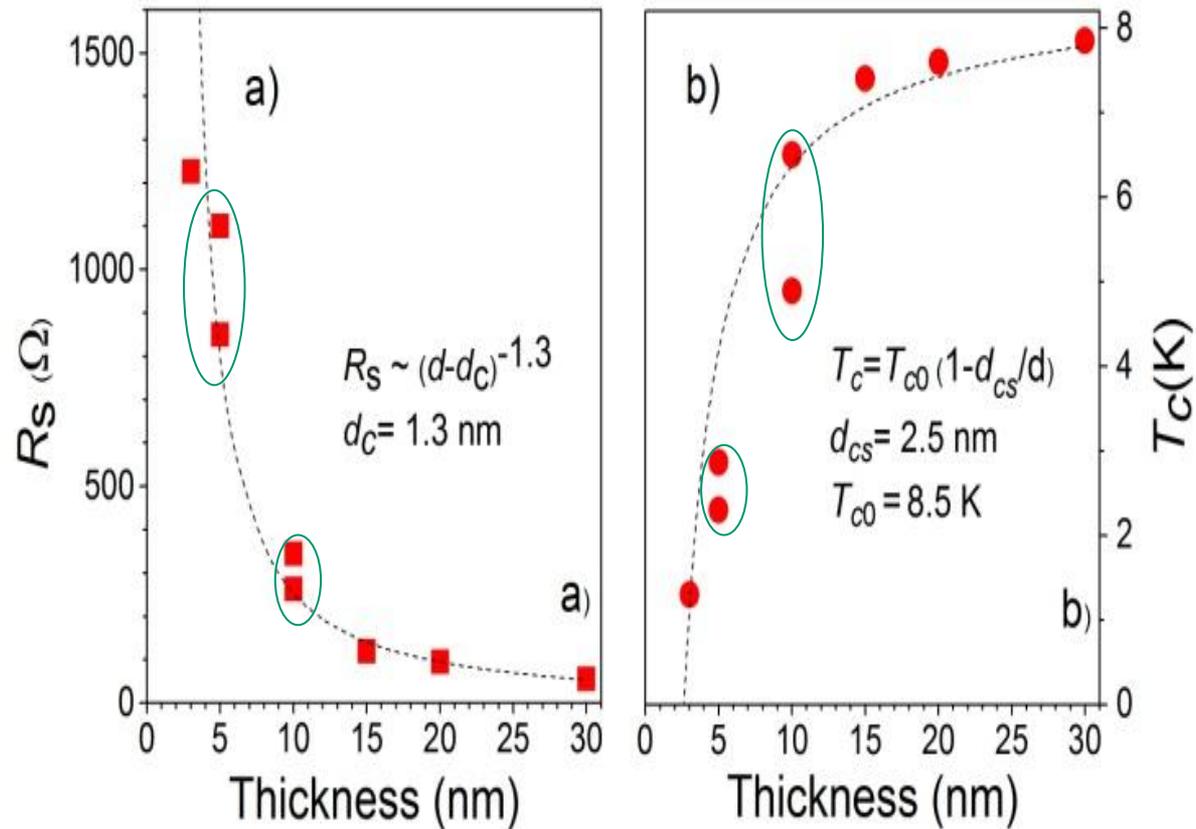


- ✓ sharp transitions @  $T_c$  for different  $d$
- ✓ sheet resistance  $R_s$  increase from 50 to 1400 Ω
- ✓ small quantum corrections due WL and EEI
- ✓  $T_c$  shift from 8 K to 1K

=> **electrically continuous/homogeneously disordered films**

- ✓ two 10 & two 5 nm films with different  $T_c$  due small change in preparation conditions

# Thickness effect



- a) Thickness dependence of  $R_S \sim (d - d_c)^{-1.3}$  in classical **percolation theory**  $\Rightarrow d_c = 1.3$  nm, minimum thickness for electrical continuity (MIT)
- b) Thickness dependence of  $T_c(d) = T_{c0}(1 - d_{cs}/d)$  within **GL calculations** (Simonin, 1986) with a **surface term** (decreased DOS)  $\Rightarrow d_{cs} \sim 2.5$  nm (good fit for optimally prepared films)

$d_{cs} > d_c \Rightarrow$  first SMT and then MIT

# Transport in MoC thin films

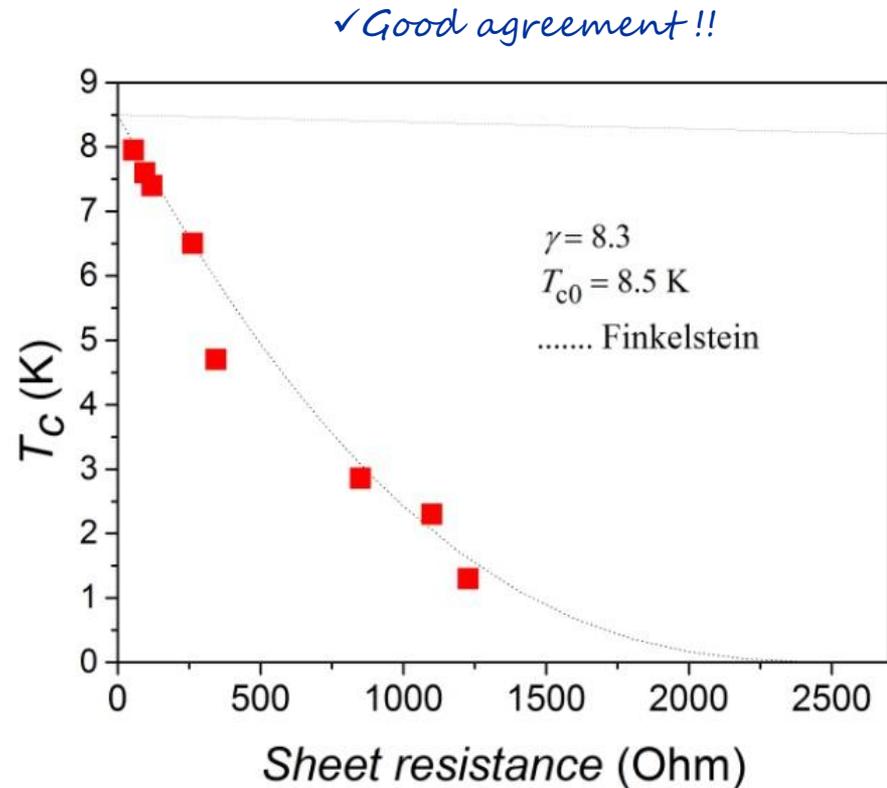
4-probe measurements in Corbino geometry

Maekawa & Fukuyama '84 / Finkel'stein '87  
 Increased diffusivity of electrons in 2D:  
 decrease of dynamical screening of Coulomb  
 repulsion which compensates SC attraction  
 ⇒ decrease of  $T_c$ , eventually  $T_c \rightarrow 0$

$$T_c = T_{c0} * \exp(\gamma) \left[ \frac{1/\gamma + t/4 - \sqrt{t/2}}{1/\gamma + t/4 + \sqrt{t/2}} \right]^{(1/\sqrt{2r})}$$

$$\gamma = \ln \left[ \frac{\hbar}{k_B T_{c0} \tau} \right] \quad r = R / (R_Q \pi)$$

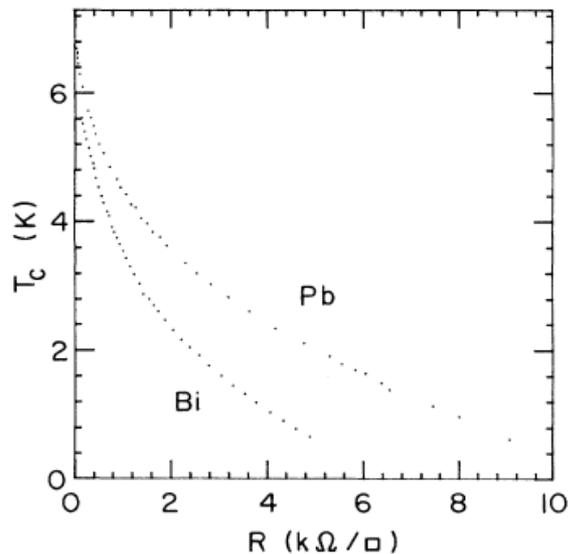
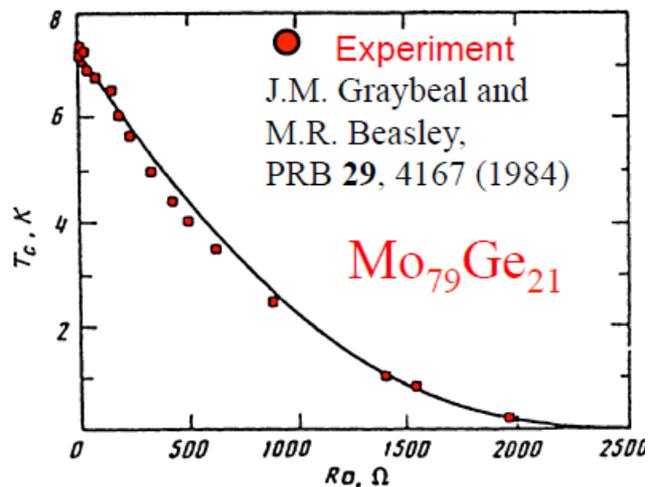
$$R_Q = h/e^2 = 25 \text{ k}\Omega$$



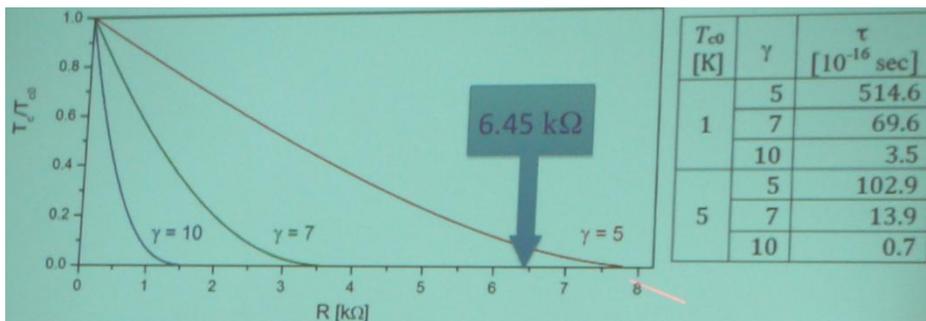
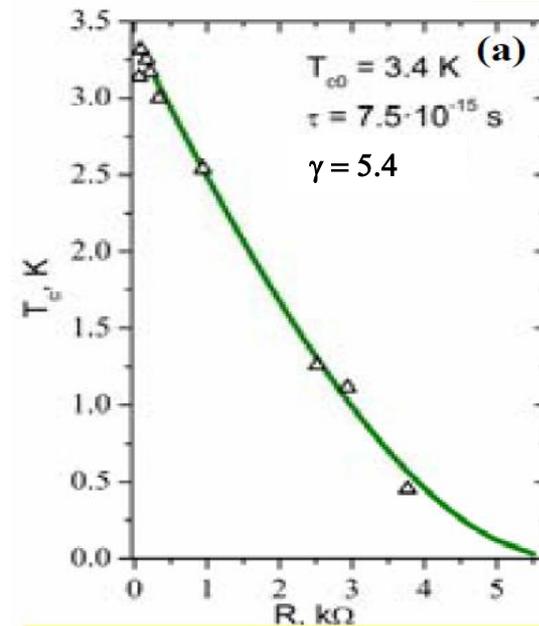
- Suppression of  $T_c$  is due to suppression of the amplitude of the sc order parameter
- Balance between sc attraction and Coulomb repulsion does not lead to full localization of electrons
- Two transitions: **superconductor => (bad) metal & metal => (fermionic) insulator**

# Agreement between Finkel'shtein model and experiment

Haviland, PRL 1989



Baturina on TiN



Fitting parameter  $\gamma \sim 5 - 8$

# Finkel'stein model

Valid for 2D superconductors:  $k_B T_{c0} \ll \hbar/\tau \ll \hbar D/d^2$

$\tau$  – relaxation time of qp momentum in normal state

$\hbar D/d^2$  – Thouless energy related to time  $t_D$  for qp diffusion through film with thickness  $d$ .  
In 2D films  $\Rightarrow l \gg d$

If  $l \ll d$  but still  $k_B T_{c0} \ll \hbar D/d^2$

In Finkel'stein formula the scattering term  $\hbar/\tau$  must be replaced by Thouless energy  $\hbar D/d^2 = (\hbar/\tau)(l/d)^2$

$$T_c = T_{c0} * \exp(\gamma) \left[ \frac{1/\gamma + t/4 - \sqrt{t/2}}{1/\gamma + t/4 + \sqrt{t/2}} \right]^{(l/\sqrt{2}r)}$$

$$\gamma = \ln \left[ \frac{\hbar}{k_B T_{c0} \tau} \right] \quad r = R/(R_Q \pi)$$

$$\gamma' = \ln \left[ \frac{\hbar D}{d^2 k_B T_{c0}} \right] = \ln \left[ \frac{\hbar}{\tau k_B T_{c0}} \left( \frac{l}{d} \right)^2 \right]$$

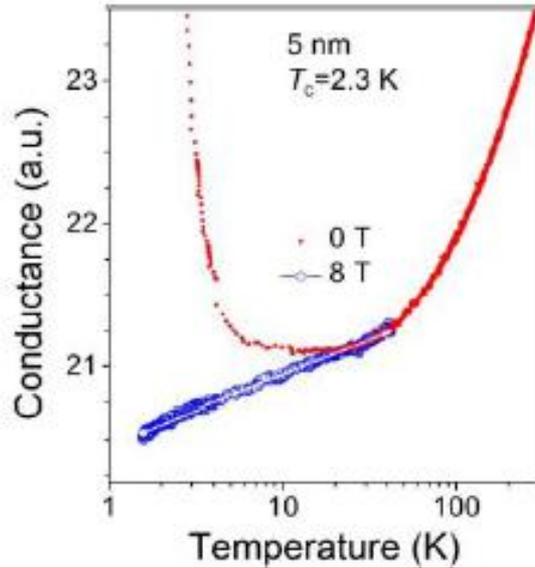
but this make much smaller effect on  $T_c \dots$

In the following we **determine the Thouless energy** in MoC films  
and compare with  $k_B T_{c0}$  and  $\hbar/\tau$

# Thouless energy: 2D vs 3D character of MoC films

Disordered metal: Bloch-Gruneisen ( $dR/dT > 0$ ) + quantum corrections to sheet resistance ( $dR/dT < 0$ )

Temperature dependence sheet conductance of MoC



Experiment:  
3D to 2D transition at low temperatures

$$L_T = \sqrt{2\pi\hbar D / (k_B T)} \sim d @ 30 - 40 \text{ K}$$

i.e.  $2\pi\hbar D / d^2 = 30 - 40 \text{ K}$

$$\Rightarrow k_B T_{c0} < (hD/d^2 \sim 10 k_B T_c) \ll \hbar/\tau$$

$$\Rightarrow l \ll d$$

We have only quasi 2D electrons in MoC

Quantum corrections = weak localization + Altshuler-Aronov can be used to test 2D or 3D character of the electron transport

$$\text{In quasi-2D: } l < d < \xi, L_T$$

$l$ : mean free path,  $d$ : film thickness,  $\xi$ : coherence length

$L_T$ : thermal coherence length  
 $D$ : diffusion coefficient

$$L_T = \sqrt{2\pi\hbar D / (k_B T)}$$

WL + AA in conductivity  $\Rightarrow$

$$\frac{\Delta G^{WL}(T) + \Delta G^{AA}(T)}{G_{00}} = A \cdot \ln \left[ \frac{k_B T \tau}{\hbar} \right]$$

$$\text{In 3D: } l, L_T < d < \xi$$

WL + AA in conductivity  $\Rightarrow$

$$\Delta G^{AA} + \Delta G^{WL} = A\sqrt{T} + BT^{p/2}$$

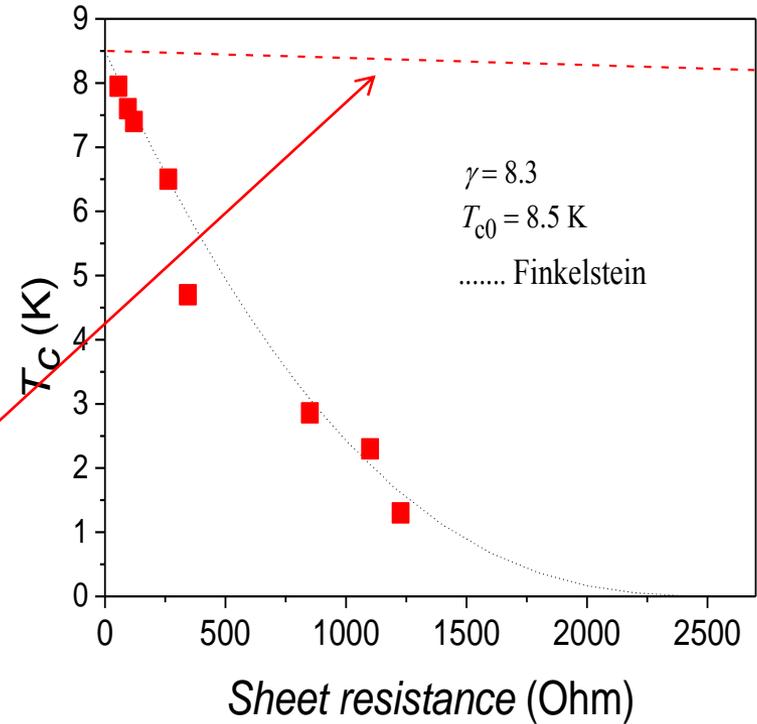
# Determination of Thouless energy from $B_{c2}$

- We measured  $B_{c2}(T)$  from  $R_S(T, B)$
- We determined  $B_{c2}(0) = 0.69(dH_{c2}/dT)T_c$ ;  
also  $\xi(0) = \sqrt{(\Phi_0/2\pi B_{c2}(0))}$
- Diffusion constant  $D = \frac{0.407\pi k_B}{e} \left(\frac{dH_{c2}}{dT}\right)^{-1}$
- transverse Thouless energy  $\pi\hbar D/d^2$  determined

**=>> Thouless energy is below 100 K  
for all MoC films (see Table)**

$$k_B T_{c0} < (\hbar D/d^2 \sim 10 k_B T_c) \ll \hbar/\tau$$

**but then the renormalized Finkelstein  
makes small effect on  $T_c$**



(Same arguments hold for MoGe, Graybeal & Beasley,  
TiN, Baturina, .....)

Effectively Finkelstein mechanism does not work  
What is the real mechanism of  $T_c$  suppression ?

# $k_F l$ from Hall & resistivity measurements

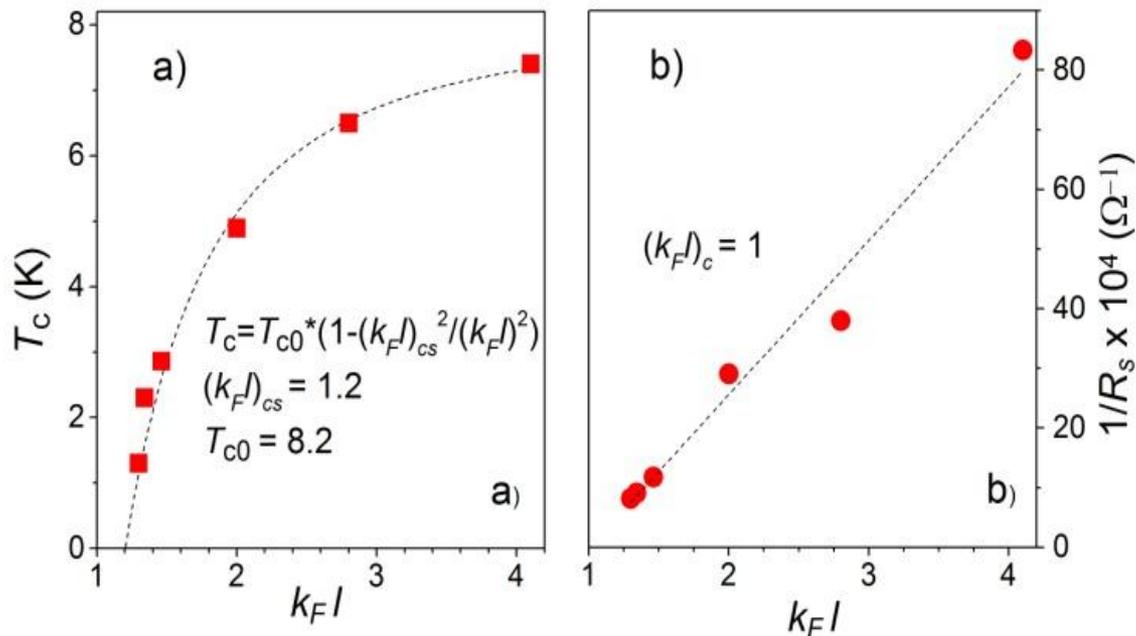
- We measured the Hall coefficient from Hall voltage deduced from field sweeps  $\pm 8\text{T}$  @ 200 K
- Charge-carrier density determined  $n \sim 10^{23} \text{ cm}^{-3}$  not changing upon decrease of thickness (!!)
- Ioffe-Regel product  $k_F l$  determined; drops from 4.1 (15nm) to 1.3 (3 nm)

$$k_F l = \frac{\hbar(3\pi^2)^{2/3}}{e^{5/3}} \left[ \frac{R_H^{1/3}}{R_{\square} d} \right]$$

$d$ [nm]	$R_s$ [ $\Omega$ ] @ 288 K	$T_c$ (K)	$R_H \times 10^{11}$ [ $\Omega \text{mT}^{-1}$ ]	$N \times 10^{23} \text{ cm}^{-3}$	$k_F l$	$H_{c2}$ [T]	$\xi$ [nm]	$D$ [ $\text{cm}^2/\text{s}$ ]	$\pi^2 \hbar D / d^2$ [K]
30	56	7.95	-	-	-	-	-	-	-
20	95	7.6	-	-	-	-	-	-	-
15	120	7.4	3.75	1.7	4.1	10.7	5.48	0.52	17.4
10	263	6.5	3.75	1.7	2.8	9.4	5.78	0.53	40
10	344	4.9	3.13	1.9	2	9.5	5.8	0.39	29.4
5	850	2.86	3.8	1.7	1.46	5.3	7.8	0.39	118
5	1100	2.3	3.8	1.7	1.34	5.3	7.8	0.33	100
3	1227	1.3	3.9	1.7	1.3	-	-	-	-

# $T_c$ versus $k_F l$

- We found that  $T_c$  follows the best  $k_F l$ , better than Finkelstein  $T_c (R_s)$ , even films with the same thickness but different  $T_c$  and  $R_s$  are well fitted.
- The data can be fit to the Anderson localization model  $T_c = T_{c0}(1-[(k_F l)_c^2/(k_F l)^2])$  with  $(k_F l)_{cs} \approx 1.2$  and  $T_{c0} = 8.2$  K.
- sheet conductance  $1/R_s$  as a function of  $k_F l$  is almost linear with  $(k_F l)_c \rightarrow 1$



$(k_F l)_{cs} > (k_F l)_c \Rightarrow$  first SMT and then MIT

## **II. Local DOS by STM/S**



# STM NEAR SIT TRANSITION

Superconductivity:  
macroscopic wave function  
with amplitude  $\Delta$  and phase  $\varphi$

$$\Psi = \Delta e^{i\varphi(r)}$$

## Fermionic mechanism

Disorder-enhanced Coulomb int.  
destroys Cooper pairs => **SMT**  
At higher disorder bad metal goes  
to Fermi insulator via **MIT**  
**Amplitude fluctuations**

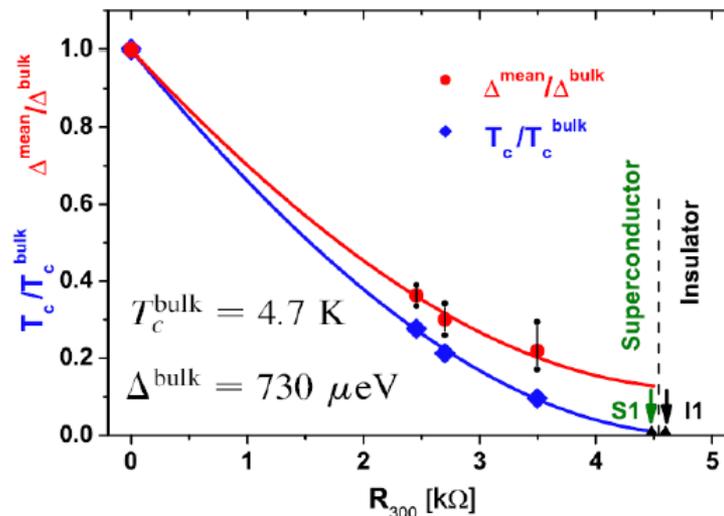
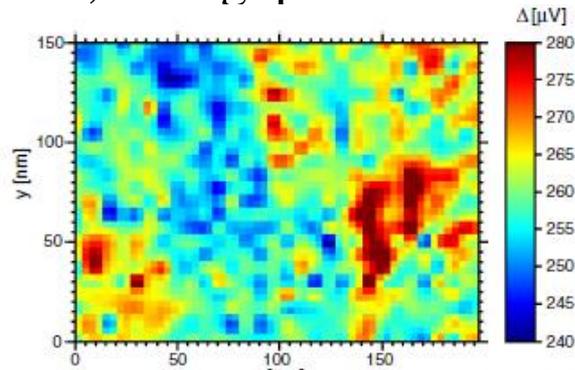
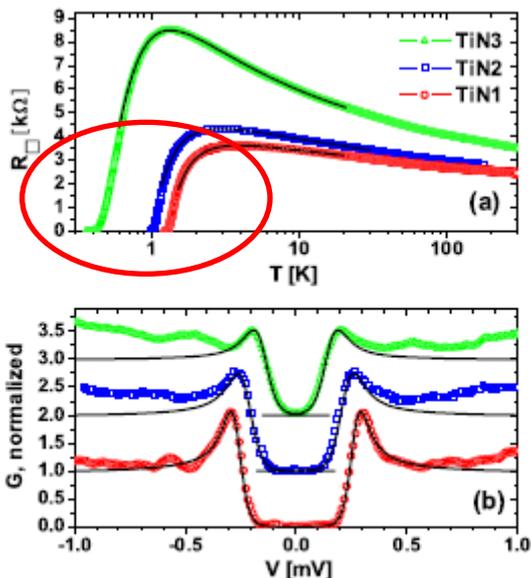
## Bosonic mechanism

Superconductor => directly to insulator **SIT**  
Cooper pairs survive with finite  $\Delta$   
without long range phase coherence  
**Phase fluctuations**

Local studies of superconductivity ( $\Delta$ ) by  
Scanning Tunneling Spectroscopy are challenging

# Scanning tunneling spectroscopy in ultrathin TiN films

Film thickness 3-5 nm, coherence length  $\xi=10$  nm, strong quantum corrections

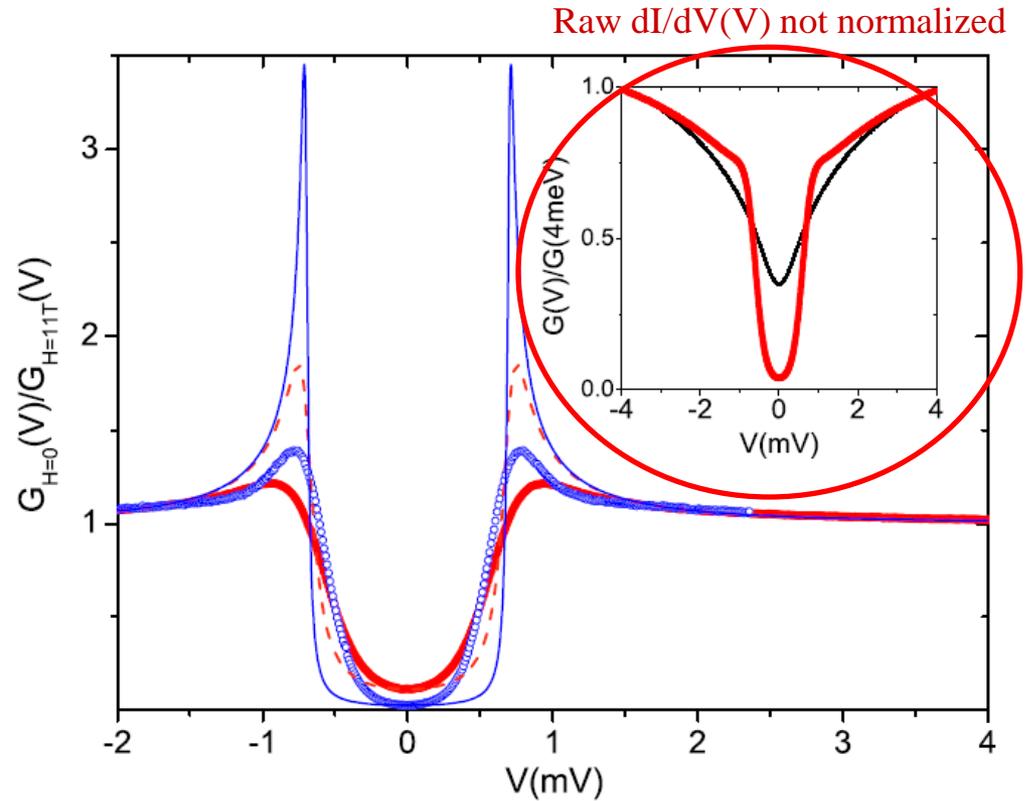
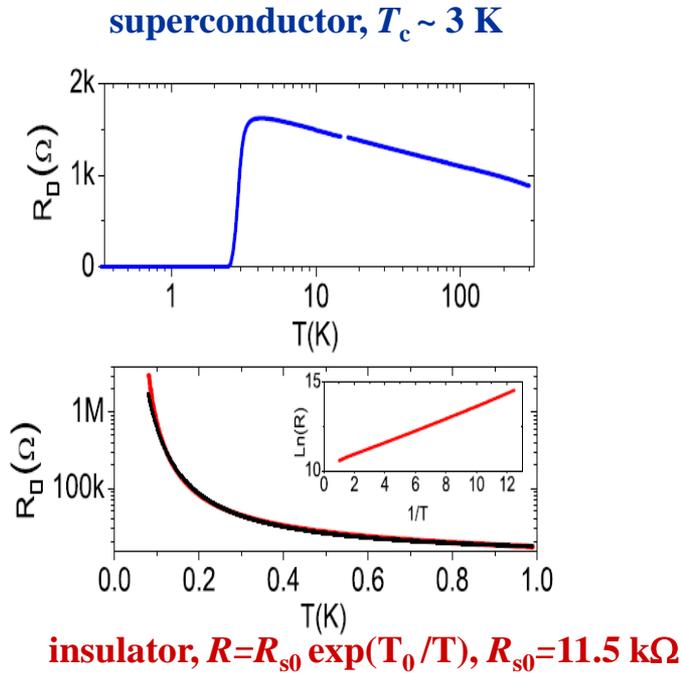


	$R_{300}$ k $\Omega$	$T_c$ K	$\bar{\Delta}$ μeV	$\sigma$ μeV	$\sigma/\bar{\Delta}$	$\bar{\Delta}/k_B T_c$
TiN1	2.45	1.3	265	11	0.04	237
TiN2	2.7	1.0	220	13	0.06	255
TiN3	3.5	0.45	160	...	...	413

Disorder driven:

decrease of  $T_c$ , inhomogeneity of gap  $\Delta$  (20%)  
 increased  $\Delta/kT_c$ :  $T_c \Rightarrow 0$  while  $\Delta$  remains finite

# Planar tunnel junctions on real insulating film compared with superconducting film



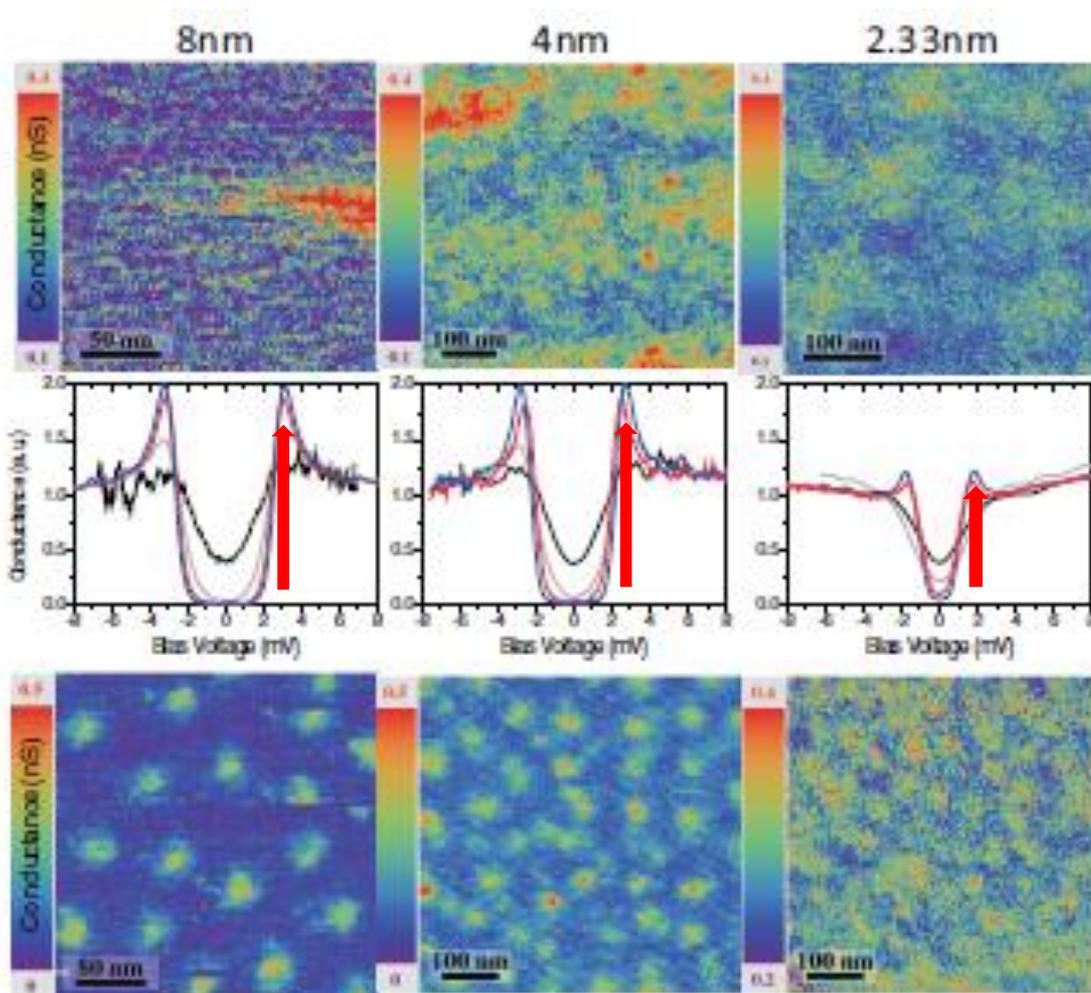
Gap remains about same in insulating phase,  
but coherence peaks are missing

# NbN films studied by Roditchev

Tunnel Cond. @ gap

Inhomogeneities

Vortex images



Fading out of vortex image  
Lost phase coherence



# STS phenomenology

On approach to SIT

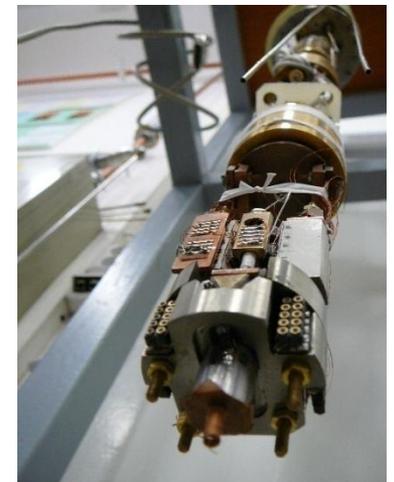
- ✓  $\Delta$  decrease more slowly than  $T_c$ ,  $2\Delta/k_B T_c$  increase
- ✓  $\Delta$  inhomogeneity on scale of  $\xi$
- ✓ pseudogap appearance
- ✓ coherence peaks in SC DOS suppression
- ✓ Fading out of vortex image

**All support bosonic scenario**

- **Is bosonic scenario universal ?**
- **Or scenario depends on material parameters ?**
- **If yes, how ?**

# STM - experimental setup in Košice

- home made STM head
- Dulcinea SPM controller by Nanotec
- **280mK**: Janis SSV 3He refrigerator
- **8T** Janis cryomagnetic system



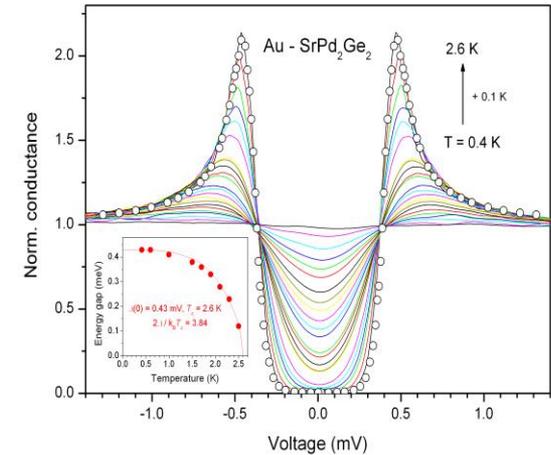
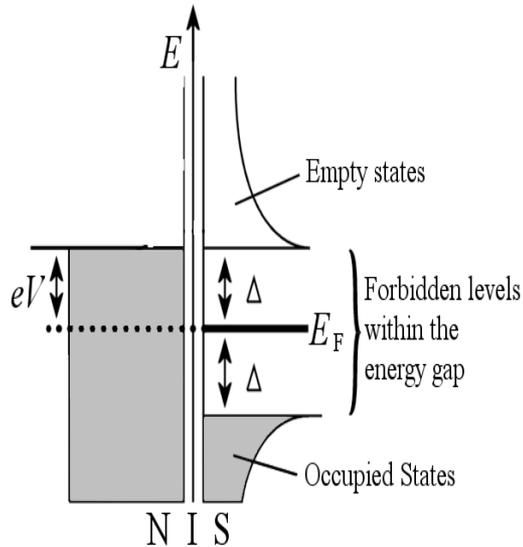
# Scanning Tunneling Spectroscopy (STS)

## S-I-N junction with Au tip

$$dI(V)/dV \propto A \int N_S(E) [\partial f(E - eV) / \partial f(eV)] dE$$

$$N_S^{BCS} = \text{Re} \left\{ \frac{E}{\sqrt{E^2 - \Delta^2}} \right\}$$

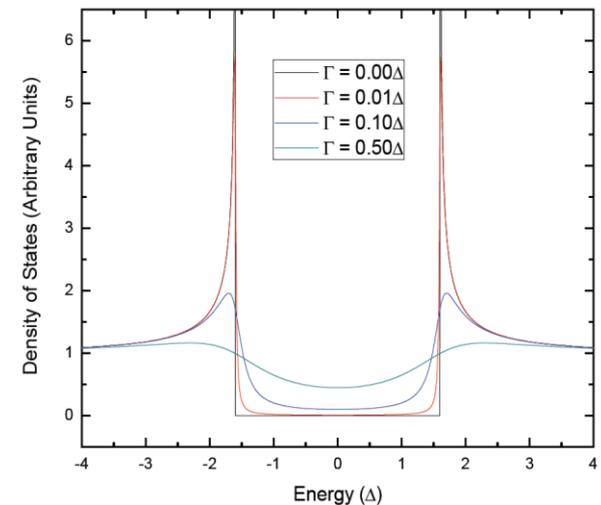
At low  $T$   $dI/dV$  is proportional to the LDOS of SC



Low temperatures are important to resolve from

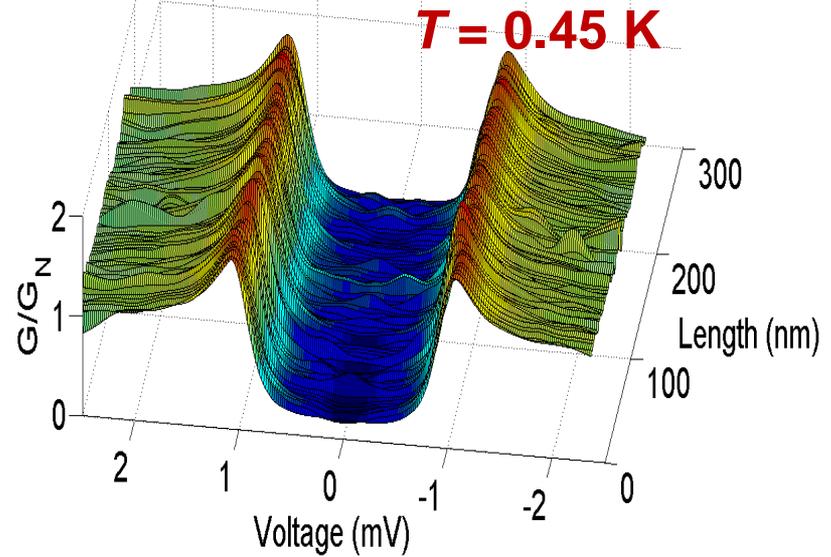
Finite lifetime effect (Dynes formula):

$$N_S^{BCS} = \text{Re} \left\{ \frac{E - i\Gamma}{\sqrt{(E - i\Gamma)^2 - \Delta^2}} \right\}$$



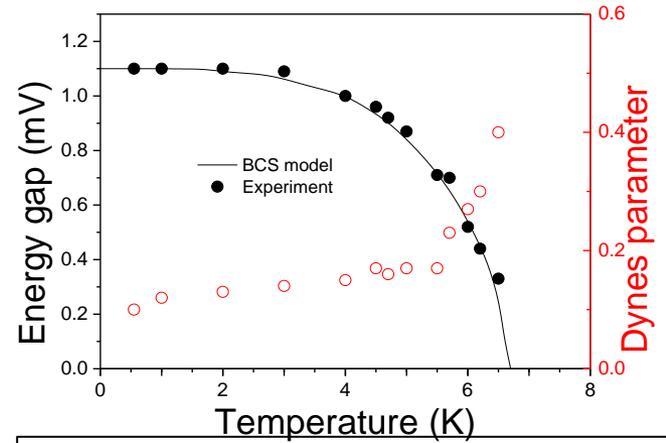
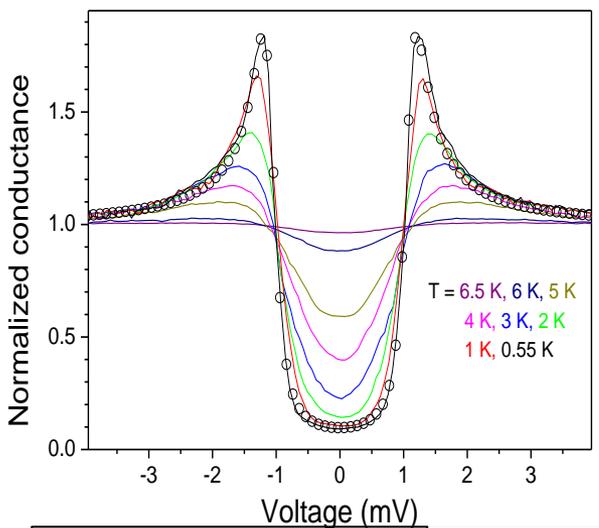
# STM on 10 nm MoC film

**$T = 0.45 \text{ K}$**



Polycrystalline films, oblate Xstal ~ 20 nm

100 spectra along 200 nm line  
very homogenous,  $\Delta$  variations less than 5%



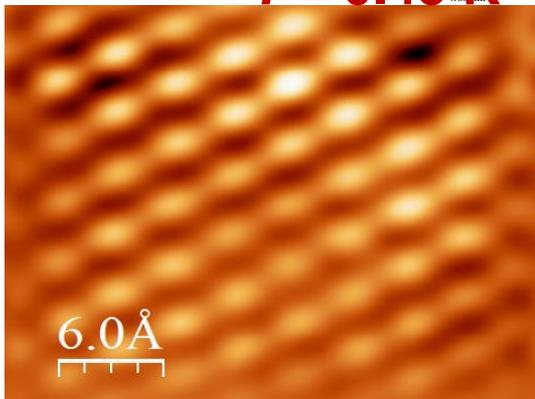
pronounced gap peaks  
In-gap states ~ 10%  
 $2\Delta/k_B T_c = 3.8$

$$N_s^{Dynes} = \text{Re} \left\{ \frac{E - i\Gamma}{\sqrt{(E - i\Gamma)^2 - \Delta^2}} \right\}$$

$\Delta(T)$  BCS-like, broadening  $\Gamma$  increases with  $T$

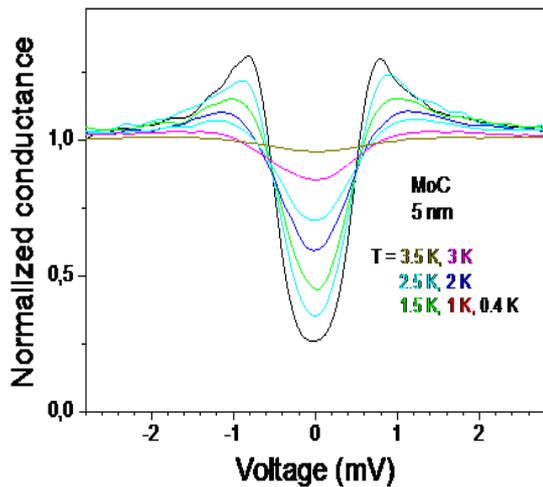
# 5 nm MoC film

$T = 0.45 \text{ K}$



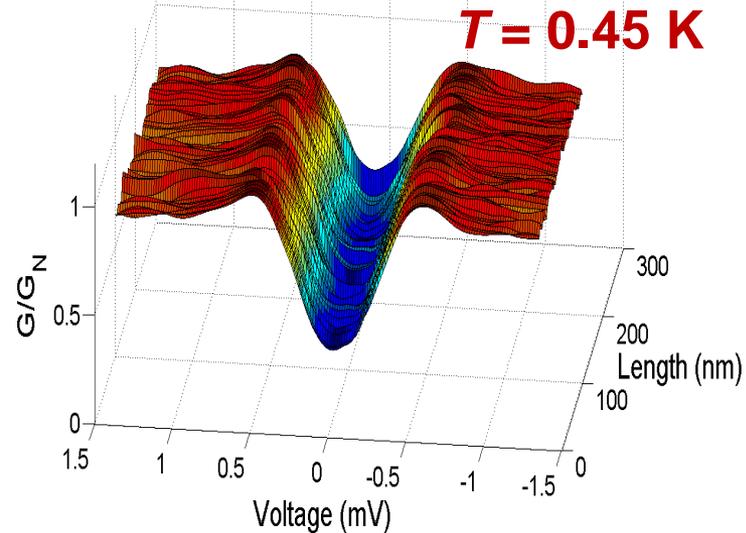
atomic lattice  
 $\Gamma$  not from some  
 dead layer

Polycrystalline films, oblate Xstal  $\sim 10 \text{ nm}$   
 corrugation  $\sim 0.7 \text{ nm}$



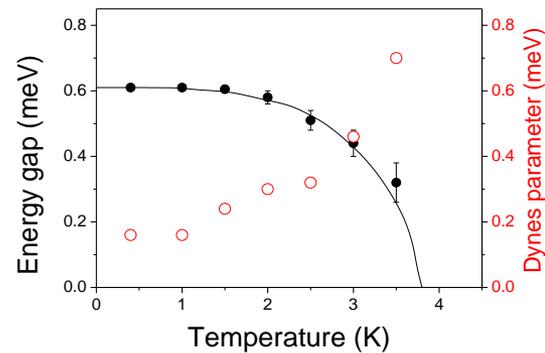
gap peaks  
 In-gap states  $\sim 30\% \sigma_n$   
 $2\Delta/k_B T_C = 3.8$

$$\Gamma = 0.3\Delta$$



Up to 100 spectra along 200 nm line  
 Variation of the peak distance  $\sim 10\%$  (see further)

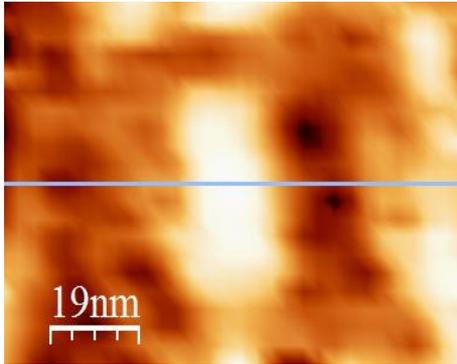
$$N_S^{Dynes} = \text{Re} \left\{ \frac{E - i\Gamma}{\sqrt{(E - i\Gamma)^2 - \Delta^2}} \right\}$$



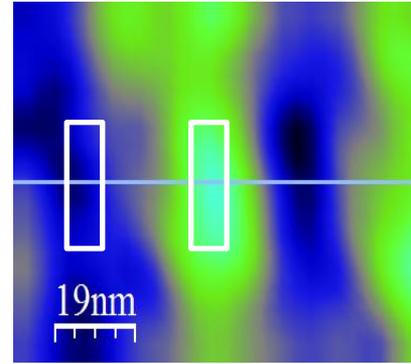
$\Delta(T)$  BCS-like, broadening  $\Gamma$  increases with  $T$

# Origin of variation of the gap value in 5 nm MoC

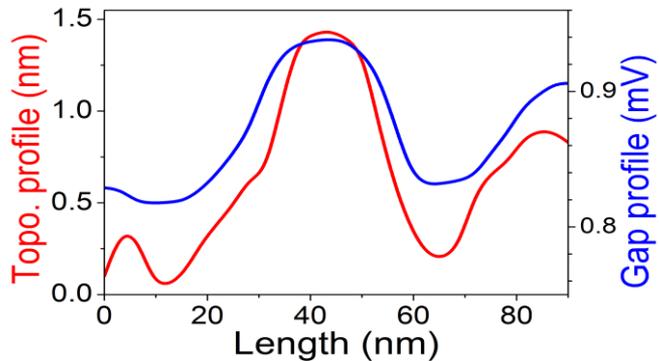
95 x 65 nm<sup>2</sup> topography



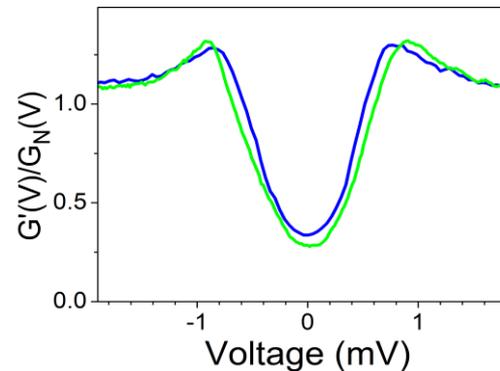
gap map of same area



Corrugation of 1.5 nm and gap profile (10% variation) along gray lines



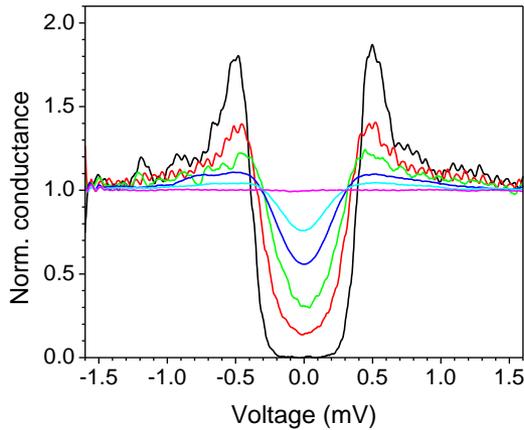
Spectra averaged over green & blue rectangles



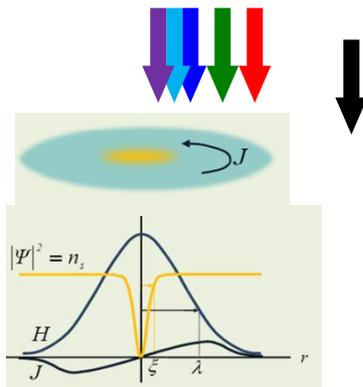
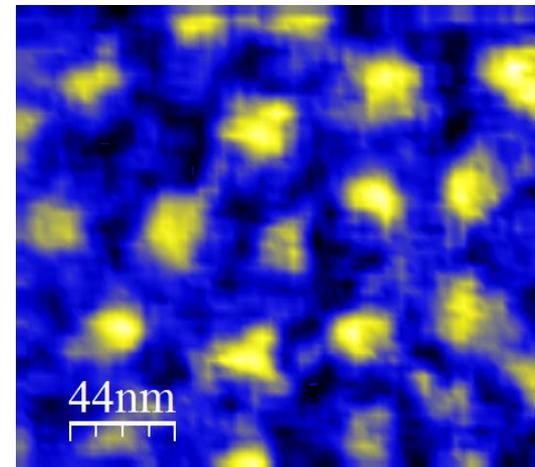
**Variation of gap-peak position follows surface corrugation !**

# Vortex imaging on 5 nm MoC film

**Spectrum along vortex in dirty SC**



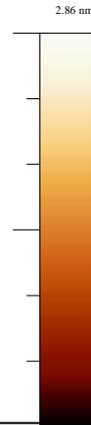
surface area  $220 \times 190 \text{ nm}^2$   
 $T = 450 \text{ mK}$ ,  $B = 1 \text{ T}$ , Abrikosov lattice  $a = 50 \text{ nm}$   
 distorted vortex lattice,



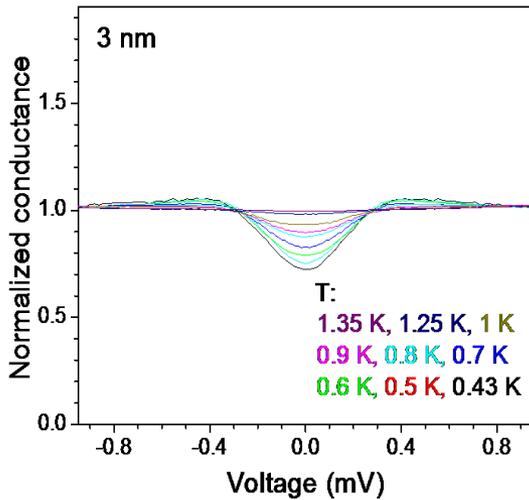
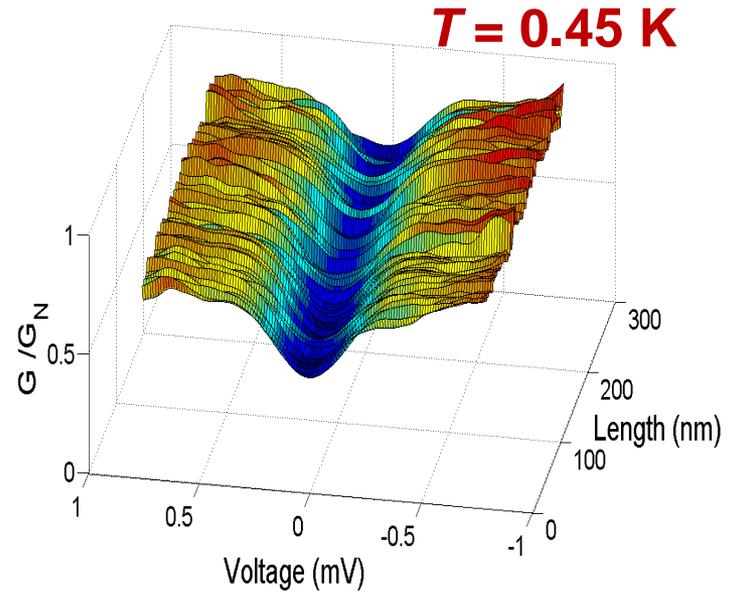
**presence of vortices in MoC suggests long range phase coherence of the superconducting condensate**

# 3 nm MoC film

**T = 0.45 K**



Polycrystalline films, oblate Xstal ~ 10 nm



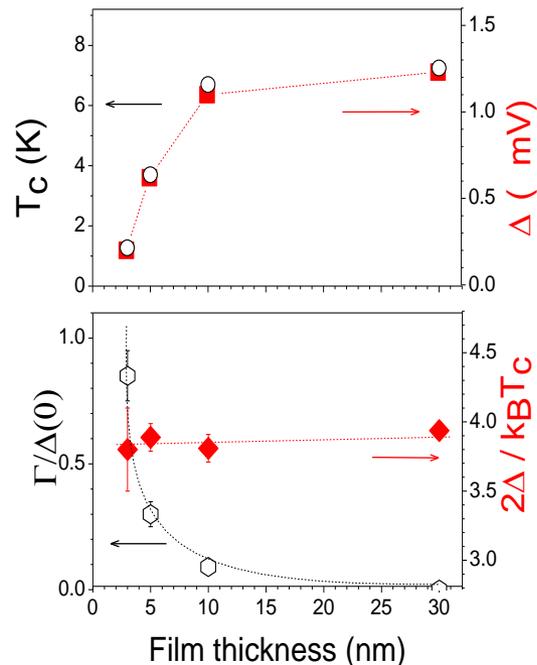
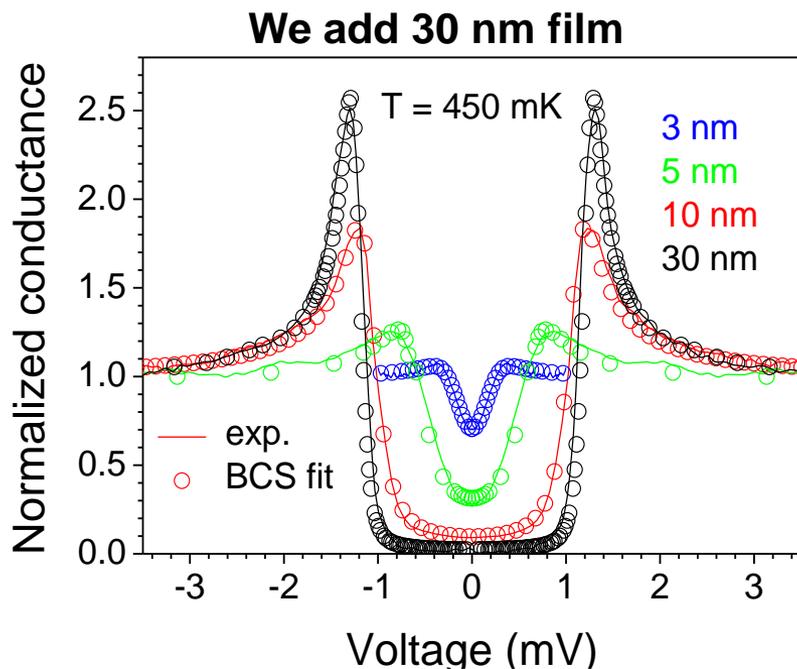
- 100 spectra along 200 nm line
- variations among spectra ?
- V-shape background appears
- suppressed gap peaks but still Dynes works
  - in-gap states ~ 80%  $\sigma_n$

$$N_S^{Dynes} = \text{Re} \left\{ \frac{E - i\Gamma}{\sqrt{(E - i\Gamma)^2 - \Delta^2}} \right\}$$

$$\Gamma = 0.8 - 0.9\Delta$$

$$2\Delta/k_B T_C = 3.5 - 4$$

# Summary of STM/S



STM spectra in MoC upon increased disorder ( $T_c$  from 8K down to 1 K &  $k_F l$  from 4 to 1 )

- Little variation of the gap
  - $T_c$  and  $\Delta$  decrease almost same way with  $2\Delta/k_B T_c \sim 3.8$
  - No pseudogap
  - Presence of vortices suggest global phase coherence
- => *Fermionic scenario!*
- Increasing in-gap states (described by Dynes  $\Gamma$ ) =>> what mechanism of pair breaking?

# Conclusions

- Ultrathin films from 30 down to 3 nm thin prepared with  $T_c$  decreasing from 8 K down to 1 K, sheet resistances up to 1400 Ohm and  $k_F l \sim 1$ ; films are not enough 2D for Finkelstein model

## *STM/S*

- sc phase/order parameter is homogeneous in space
- $T_c$  and  $\Delta$  decrease in same way with  $2\Delta/k_B T_c \sim 3.7 - 3.9$
- Increasing in-gap states ( $\Gamma$ ) or gapless SDOS

## *(CWR transmission*

- Strong pair breaking out of Mattis-Bardeen scenario )

# Questions

- Mechanism of  $T_c$  suppression for films with  $l \ll d$  ?
- Mechanism of pair breaking leading to gapless SDOS ?
- (Mechanism of strong losses in CWR ?)

Спасибо



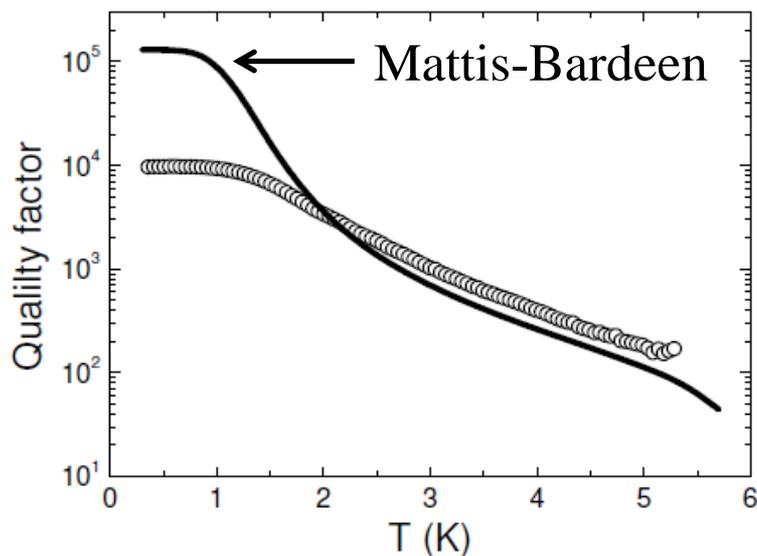
### **III. Complex conductivity in coplanar wave resonator**

# Complex conductivity from transmission of CWR

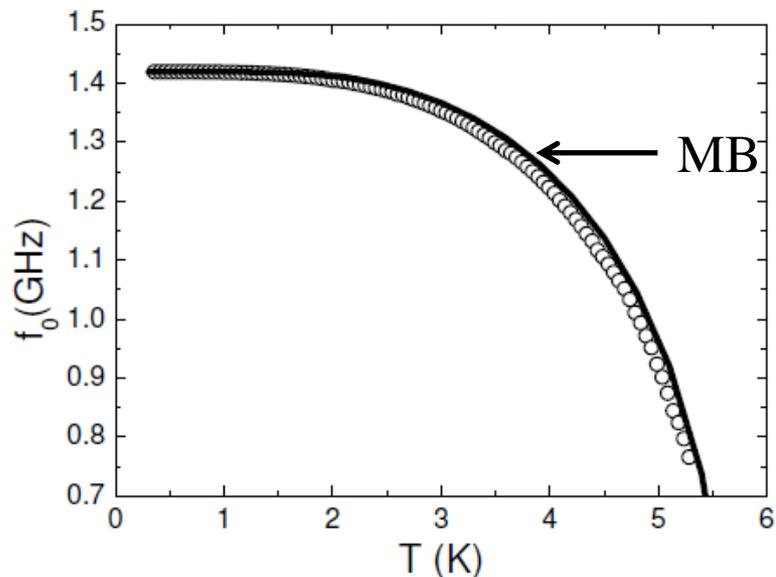
CWR patterned on 10 nm MoC film by optical lithography/etched by ion milling

Transmission measurements => temp. dependence of

- resonance frequency  $f_0$  ( $\sim$  imaginary part of impedance  $\sim$  inductance)
- quality factor  $Q$  ( $\sim$  real part of impedance  $\sim$  resistive losses)



Losses at low temperatures are much higher than predicted by Mattis-Bardeen  
Extra pair breaking present



Resonance frequency falls below Mattis-Bardeen prediction